

REMARKS

Claims 1-20 are pending in this application.

In response to the Office Communication (Paper No. 20040809) dated on August 23, 2004, in which the Examiner alleges that the Amendment filed on June 2, 2004 is non-responsive under MPEP 821.03 because such an Amendment seeks to cancel all claims 1-20 allegedly drawn to the elected invention and present new claims 21-56 allegedly drawn to a non-elected invention, Applicants hereby reinstate claims 1-20 and withdraw the previously added but never entered new claims 21-56. However, for purposes of expedition and completeness, base claims 1, 7 and 14 have been amended herein below to clearly distinguish over the cited prior art of record in order to place the application in condition for allowance.

A new title of --LIQUID CRYSTAL DISPLAY DEVICE, MEASURING METHOD FOR MEASURING AC RESIDUAL IMAGE, AND IMPROVED LIQUID CRYSTAL DISPLAY DEVICE OBTAINED BY SUCH METHOD—is hereby submitted for the Examiner's consideration and entry.

In the outstanding Office Action (Paper No. 20040303) dated on March 12, 2004, claims 1-2, 7-9 and 14-16 have been rejected under 35 USC 103(a) as being unpatentable over Ohe et al., U.S. Patent No. 5,600,464, as modified to incorporate selected features from Ota et al., U.S. Patent No. 5,831,707 for reasons stated on pages 2-5 of the Office Action (Paper No. 20040303). Separately, claims 3, 10 and 17 have been rejected under 35 USC 103(a) as being unpatentable over Ohe et al., U.S. Patent No. 5,600,464, and Ota et al., U.S. Patent No. 5,831,707, as applied to claims 1-2, 7-9 and 14-16, and further in view of Mishina et al., U.S. Patent No. 5,350,539 for reasons stated on pages 5-6 of the Office Action (Paper No.

20040303). Lastly, claims 4, 5, 6, 11-13 and 18-20 have been rejected under 35 USC 103(a) as being unpatentable over Ohe et al., U.S. Patent No. 5,600,464; Ota et al., U.S. Patent No. 5,831,707; Mishina et al., U.S. Patent No. 5,350,539 as applied to claim 3 above, and further in view of Yu et al., U.S. Patent No. 6,066,696 for reasons stated on pages 6-7 of the Office Action (Paper No. 20040303). As previously outlined in Applicants' Amendment filed on December 1, 2003, these rejections are factually incorrect. However, in the interest of expedition, base claims 1, 7 and 14 have been amended to further define how the "oriented film" is obtained in order to clearly distinguish over the cited prior art.

For example, base claims 1, 7 and 14 have been amended to further define that the "oriented film" is selected through a method for measuring an AC residue image which comprises:

- a first step of stabilize a display panel;
- a second step of measuring a brightness $B_b(V_{sig})$ of the display panel, while a signal voltage V_{sig} applied thereto is increased;
- a third step of driving the display panel for a predetermined period with a predetermined signal voltage V_{max} ,
- a fourth step of measuring a brightness $B_a(V_{sig})$ of the display panel, while the signal voltage V_{sig} applied thereto is decreased; and
- a fifth step of obtaining a value of AC residual image $\Delta B(V_{sig})$ by the following formula:
$$\Delta B(V_{sig}) (\%) = [B_a(V_{sig}) - B_b(V_{sig})] / B_b(V_{sig}).$$

Such steps are described on pages 19-20 of Applicants' original specification used to separate AC residue image from other residue images. Such measuring techniques as currently defined in Applicants' claims 1, 7 and 14, as currently amended, are **not** described or suggested by the cited prior art of record, including Ohe et al., U.S. Patent No. 5,600,464; Ota et al., U.S. Patent No. 5,831,707; Mishina et al., U.S. Patent No. 5,350,539, and Yu et al., U.S. Patent No. 6,066,696. As a

result, Applicants believe that claims 1-20 are now deemed to be allowable and this application is believed to be in condition to be passed to issue.

Should any questions remain unresolved, the Examiner is requested to telephone Applicants' attorney at the Washington DC area office at (703) 312-6600. Applicants respectfully reserve all rights to file subsequent related application(s) (including reissue applications) directed to any or all previously claimed limitations/features which have been amended or canceled, or to any or all limitations/features not yet claimed, i.e., Applicants have no intention or desire to dedicate or surrender any limitations/features of the disclosed invention to the public.

INTERVIEW:

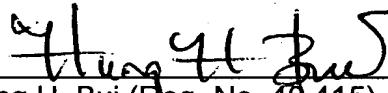
In the interest of expediting prosecution of the present application, Applicants respectfully request that an Examiner interview be scheduled and conducted. In accordance with such interview request, Applicants respectfully request that the Examiner, after review of the present Amendment, contact the undersigned local Washington, D.C. area attorney at the local Washington, D.C. telephone number (703) 312-6600 for scheduling an Examiner interview, or alternatively, refrain from issuing a further action in the above-identified application as the undersigned attorneys will be telephoning the Examiner shortly after the filing date of this Amendment in order to schedule an Examiner interview. Applicants thank the Examiner in advance for such considerations. In the event that this Amendment, in and of itself, is sufficient to place the application in condition for allowance, no Examiner interview may be necessary.

To the extent necessary, Applicants petition for an extension of time under 37 CFR §1.136. Please charge any shortage of fees due in connection with the filing of this paper, including extension of time fees, to the Deposit Account of Antonelli, Terry, Stout & Kraus, No. 01-2135 (Application No. 1113.40340X00), and please credit any excess fees to said deposit account.

Respectfully submitted,

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